

IN THE  
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Xiaofeng YANG et al.

Confirmation No.:

Application No.: Unassigned

Examiner: Unassigned

Filing Date: 04/21/2004

Group Art Unit:

Title: WHEATSTONE BRIDGE SCHEME FOR SENSOR

Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

- ☒ under 37 CFR 1.97(b), or  
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
- ☐ under 37 CFR 1.97 (c) together with either a:  
☐ Statement under 37 CFR 1.97(e), or  
☐ a \$180.00 fee under 37 CFR 1.17(p), or  
(After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
- ☐ under 37 CFR 1.97 (d) together with a:  
☐ Statement under 37 CFR 1.97(e)(1) or (2), and  
☐ a \$180.00 fee set forth in 37 CFR 1.17(p).  
(Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account **08-2025** the sum of \$0.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account **08-2025** pursuant to 37 CFR 1.25.

☒ Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Statement together with any required copies of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

☐ A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individual(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

- ☐ I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, Alexandria, VA 22313-1450. Date of Deposit: \_\_\_\_\_

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Respectfully submitted,

Xiaofeng YANG et al.

By

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The USPTO has waived the requirement under 37 CFR 1.98(a)(2)(i) to submit copies of U.S. patents and U.S. patent application publications when citing and submitting an Information Disclosure Statement in a patent application filed after June 30, 2003 and in an international application that has entered the national stage under 37 USC §371 after June 30, 2003. Accordingly, copies of these types of documents are not being supplied in connection with this application. Reference is being made to Pre-OG Notice from Office of Patent Legal Administration dated July 25, 2003, *Information Disclosure Statements May Be Filed Without Copies of U.S. Patents and Published Applications in Patent Applications filed after June 30, 2003.*

Form PTO-1449 (MODIFIED)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 200310116-1		SERIAL NO. Unassigned		
<b>INFORMATION DISCLOSURE CITATION</b> Date Filed: April 21, 2004 (Use several sheets if necessary)				APPLICANT Xiaofeng YANG et al.				
				FILING DATE 04/21/2004		GROUP ART UNIT Unassigned		
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE	
	A1	6,615,668 B2	09/09/2003	TOYODA ET AL.				
	A2	6,578,426 B2	06/17/2003	IMAI ET AL.				
	A3	6,211,540 B1	04/03/2001	TAKAHASHI ET AL.				
	A4	5,948,965	09/07/1999	UPCHURCH ET AL.				
	A5	5,595,942	01/21/1997	ALBRECHT				
<b>FOREIGN PATENT DOCUMENTS</b>								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	A6	CARL V. THOMPSON et al. "Submicron and Nano Materials: Science and Engineering," Department of Materials Science and Engineering, 13 Sheets.						
	A7	M. HLIWA et al., "Intramolecular Wheatstone Bridge," Intramolecular Wheatstone, September 22, 2003, 2 pages, <a href="http://www.cemes.fr/Oper_recherche/nanosciences/9-%20Molecul...">http://www.cemes.fr/Oper_recherche/nanosciences/9-%20Molecul...</a>						
	A8	D. HOADLEY et al., "Mechanical Strain, Conductance Fluctuations, and Dynamics of Single Tunneling Defects," W. M. Keck Microfabrication Facility, August 5, 2003, 1 page, <a href="http://kmf.pa.msu.edu/Research/resrch04.asp">http://kmf.pa.msu.edu/Research/resrch04.asp</a> .						
	A9	Y. LEE et al., "High-Cycle Fatigue Test of Nanoscale Si and SiO <sub>2</sub> Wires Based on AFM Technique," Department of Mechanical Engineering, Faculty of Science and Engineering, Ritsumeikan University, 2 pages.						
	A10	M. LUTWYCHE et al., "5X5 2D AFM Cantilever Arrays A First Step Towards A Terabit Storage Device," Sensors and Actuators, 1999, pages 89-94, vol. 73.						
	A11	T. ONDARCUHU et al., "Nanotube Devices," August 5, 2003, 5 pages, <a href="http://www.cemes.fr/Oper_recherche/nanosciences/6%20-%20Mole">http://www.cemes.fr/Oper_recherche/nanosciences/6%20-%20Mole</a> .						
	A12	"Nano Probe", Precision Engineering, September 22, 2003, 2 pages, <a href="http://pe.wtb.tue.nl/Personal/bos/probe.htm">http://pe.wtb.tue.nl/Personal/bos/probe.htm</a> .						
<b>EXAMINER</b>				<b>DATE CONSIDERED</b>				
* <b>EXAMINER:</b> Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include any copy of this form with next communication to applicant.								